MOSFET - Power, N-Channel, SUPERFET[®] III, FAST

650 V, 55 mΩ, 47 A

NTP055N65S3H

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provides superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III FAST MOSFET series helps minimize various power systems and improve system efficiency.

Features

- 700 V @ $T_J = 150^{\circ}C$
- Typ. $R_{DS(on)} = 45 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 96 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 880 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

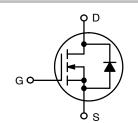
- Telecom / Server Power Supplies
- Industrial Power Supplies
- EV Charger
- UPS / Solar



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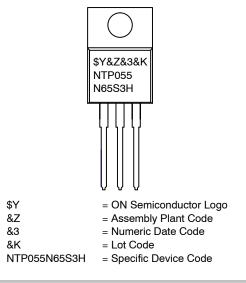
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V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	55 m Ω @ 10 V	47 A





MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Paran	Value	Unit V	
V _{DSS}	Drain to Source Voltage			650
V _{GSS}	Gate to Source Voltage	DC	±30	V
		AC (f > 1 Hz)	±30	V
Ι _D	Drain Current	Continuous (T _C = 25°C)	47	А
		Continuous (T _C = 100°C)	30	
I _{DM}	Drain Current	Pulsed (Note 1)	132	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		491	mJ
I _{AS}	Avalanche Current (Note 2)		6.9	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		3.05	mJ
dv/dt	MOSFET dv/dt		120	V/ns
	Peak Diode Recovery dv/dt (Note 3)		20	
P _D	Power Dissipation	(T _C = 25°C)	305	W
		Derate Above 25°C	2.44	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
ΤL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		260	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise specified)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 6.9 \text{ A}, R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} \le 23.5 \text{ A}, \text{ di/dt} \le 200 \text{ A/}\mu\text{s}, V_{DD} \le 400 \text{ V}, \text{ starting } T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.41	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
NTP055N65S3H	NTP055N65S3H	TO-220-3LD (Pb-Free / Halogen Free)	50 Units / Tube

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
FF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 1 mA, T_J = 25°C	650			V
		V_{GS} = 0 V, I _D = 1 mA, T _J = 150°C	700			V
$\Delta \text{BV}_{\text{DSS}}\!/\!\Delta\text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 10 mA, Referenced to 25°C		0.63		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$		1	2	μA
		V_{DS} = 520 V, T_{C} = 125°C		3.2		1
I _{GSS}	Gate to Body Leakage Current	V_{GS} = ±30 V, V_{DS} = 0 V		1	±100	nA
N CHARACTE	ERISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 4.8 \text{ mA}$	2.4		4.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V_{GS} = 10 V, I _D = 23.5 A		45	55	mΩ
9fs	Forward Transconductance	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 23.5 \text{ A}$		52		S
YNAMIC CHA	RACTERISTICS					
C _{iss}	Input Capacitance	V_{DS} = 400 V, V_{GS} = 0 V, f = 250 kHz		4305		pF
Coss	Output Capacitance			73		pF
Coss(eff.)	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		880		pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		127		pF
Q _{g(tot)}	Total Gate Charge at 10 V			96		nC
Q _{gs}	Gate to Source Gate Charge	V_{DS} = 400 V, I _D = 23.5 A, V _{GS} = 10 V (Note 4)		23		nC
Q _{gd}	Gate to Drain "Miller" Charge			27		nC
ESR	Equivalent Series Resistance	f = 1 MHz		0.6		Ω
WITCHING CH	IARACTERISTICS					
t _{d(on)}	Turn-On Delay Time			30		ns
t _r	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 23.5 \text{ A},$		16		ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 V, R_g = 4.7 \Omega$ (Note 4)		90		ns
t _f	Turn-Off Fall Time			2.8		ns
OURCE-DRAI	N DIODE CHARACTERISTICS					.
I _S	Maximum Continuous Source to Drain Diode Forward Current				47	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current				132	A
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 23.5 A			1.2	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 23.5 A,		481		ns
Q _{rr}	Reverse Recovery Charge	$dI_{\rm F}/dt = 100 \text{ A}/\mu \text{s}$		7.7		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

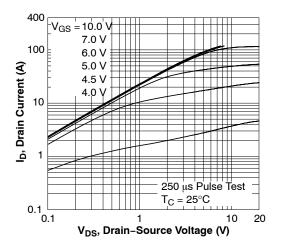
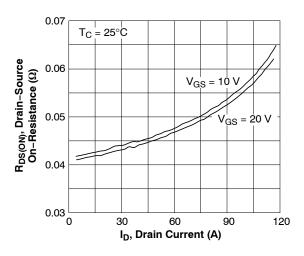
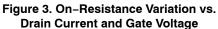


Figure 1. On-Region Characteristics





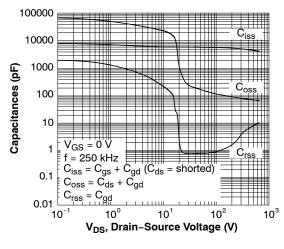


Figure 5. Capacitance Characteristics

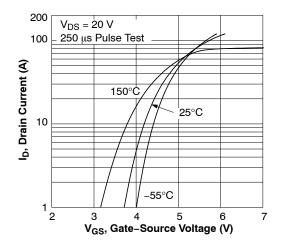
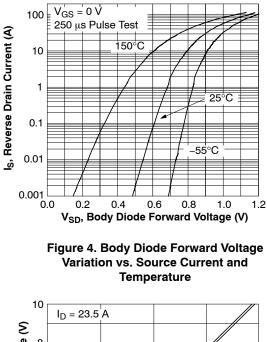
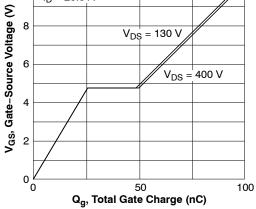


Figure 2. Transfer Characteristics







TYPICAL PERFORMANCE CHARACTERISTICS (continued)

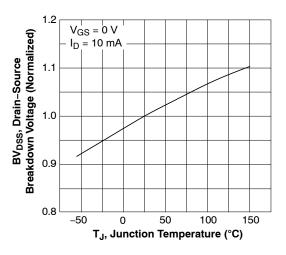


Figure 7. Breakdown Voltage Variation vs. Temperature

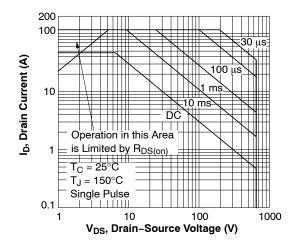


Figure 9. Maximum Safe Operating Area

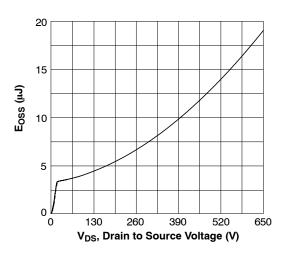


Figure 11. E_{OSS} vs. Drain to Source Voltage

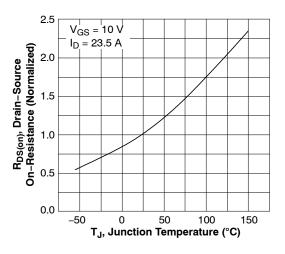


Figure 8. On–Resistance Variation vs. Temperature

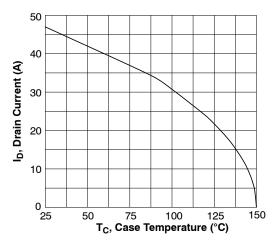


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

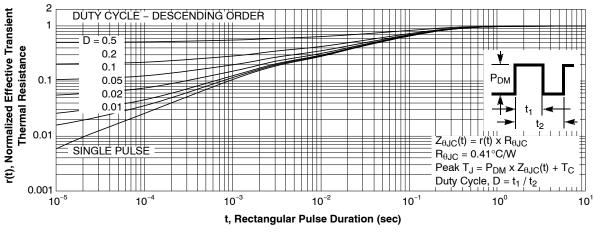
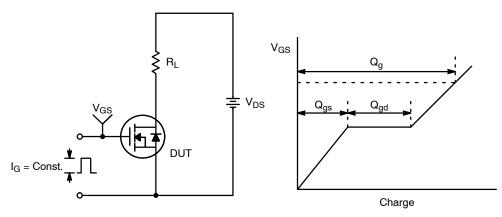


Figure 12. Transient Thermal Response Curve





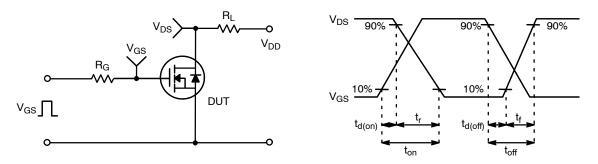


Figure 14. Resistive Switching Test Circuit & Waveforms

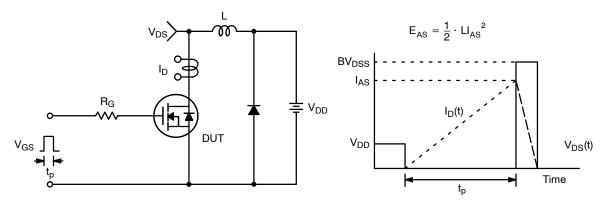


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

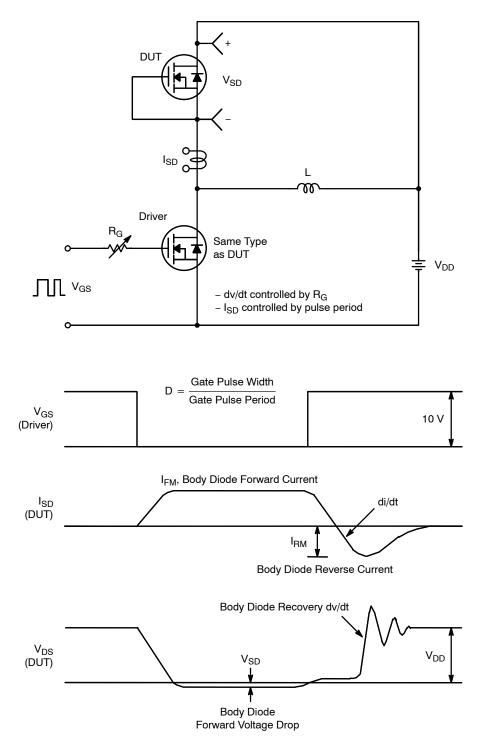
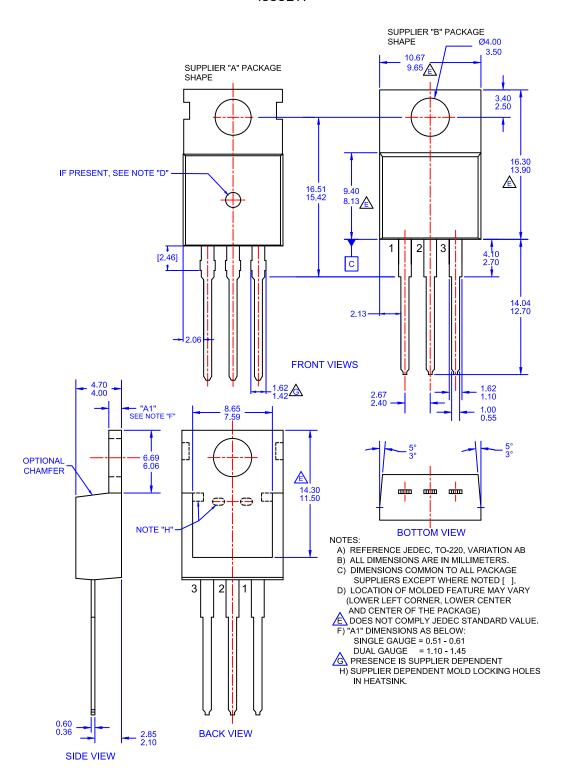


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

PACKAGE DIMENSIONS

TO-220-3LD CASE 340AT ISSUE A



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